

Search Notes**Application/Control No.**

10/822,522

Examiner

Charles R. Kasenge

Applicant(s)/Patent under Reexamination

HSHIEH ET AL.

Art Unit

2125

SEARCHED

Class	Subclass	Date	Examiner
700	90	7/22/2006	CK
	95		
	96		
	99		
	108		
	109		
	110		
705	7		
	8		
	26		
	27		
	28,29		
340	540		
700	121	8/29/2007	CK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
705	7	8/29/2007	CK
	28		
700	121		
See Attached Interference Search		8/29/2007	CK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST; terms: (semiconductor with (fabrication production manufacturing)), lot, MES, WIP, yield, (ship\$4 deliver\$3)	7/22/2006	CK
EAST; terms: ((semiconductor lot substrate workpiece wafer die IC \$5chip (integrated with circuit)) with	1/10/2007	CK
terms cont.: (suppl\$6 provid\$3 ship\$4 deliver\$3 transport\$7 transfer\$4) with (facility factory foundry plant provider fab))		
Assignee and Inventor Search	8/29/2007	CK